START-02-F-00430

SAMPLING TRIP REPORT

SITE NAME:

Cornell-Dubilier Electronics

EPA ID NO.:

GΖ

SAMPLING DATE: 16 July 1996

1. Site Location: Refer to Figure 1

2. Sample Locations: Refer to Figure 2

3. Sample Descriptions: Refer to Table 1

4. Laboratory Receiving Samples:

Sample Type

Name and Address of Laboratory

Soil/Aqueous - TCL PCBs and Total Metals for Ag, Cr, Cd, Hg,

ICM Laboratories 1152 Route 10 Randolph, NJ 07869

and Pb

5. Sample Dispatch Data:

> The following samples were hand-delivered by Region II START personnel to ICM Laboratories on 17 July 1996 at approximately 1015 hours: 18 soil samples and one aqueous sample for TCL PCB and Total Metals (Ag, Cr, Cd, Hg, and Pb) analyses.

6. On-Site Personnel:

<u>Name</u>	<u>Company</u>	<u>Duties on Site</u>
Nick Magriples Christoph Stannik Jennifer Leahy Swamy Ketha Joann Wagner	Region II EPA Region II START Region II START Region II START Region II START	Task Monitor Task Manager/Sampler Documentation/Sample Management Sampler/Equipment Decontamination Sampler/Equipment Decontamination
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7. Weather Conditions:

Sunny; approximately 80° F.; winds N/NW, estimated 0 to 10 mph.

8. Additional Comments:

A total of 18 soil samples, including one field duplicate sample, were collected for TCL PCBs, and Total Metals for Ag, Cr, Cd, Hg, and Pb analyses. Sample No. CDE-TP8A was collected as a field duplicate of Sample No. CDE-TP6A. In addition, one rinsate blank (Sample No. CDE-RIN3) and one matrix spike/matrix spike duplicate (MS/MSD) sample (Sample Location No. CDE-TP1A) were collected and delivered to the laboratory to meet QA/QC requirements for the QA-2 data quality objective level.

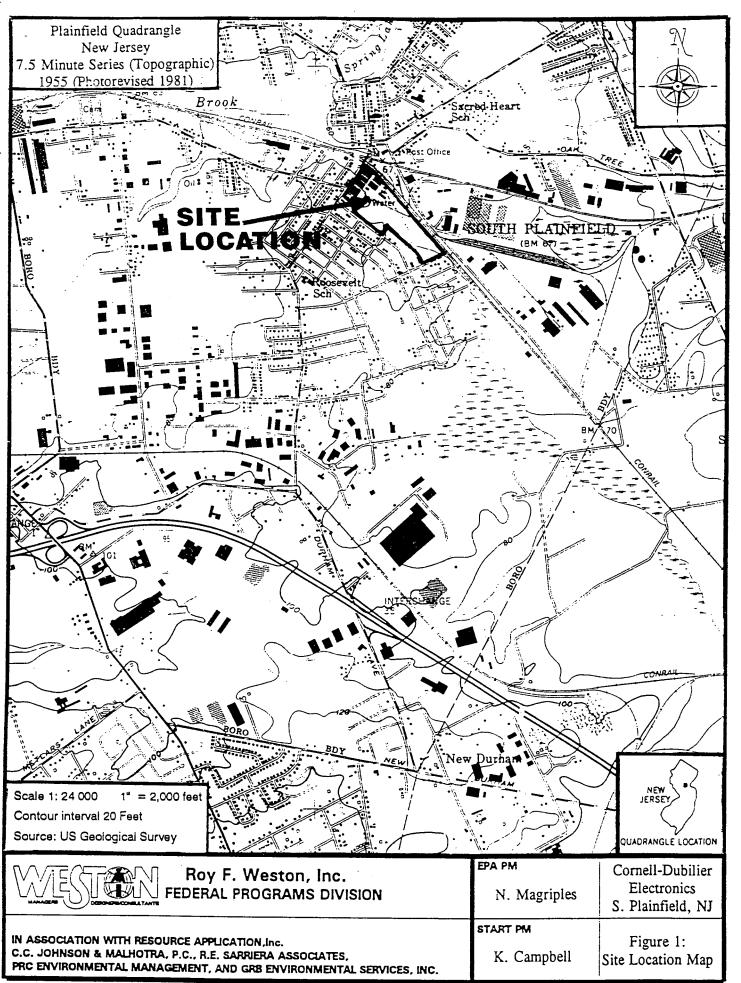
After collecting soil samples from the Test Pit No. 1 location, the TM indicated that it was acceptable for START to collect subsequent test pit soil samples directly from the excavator bucket without placing the soil in a stainless steel bowl for homogenization. The sampling QA/QC Plan indicated that the soil aliquot would be placed in a stainless steel and homogenized prior to sample collection.

At Test Pit Location No. 4, a large amount of wood and miscellaneous debris was encountered; a crushed, empty 55-gallon drum was present in the excavated material. Due to the amount of non-soil material excavated from the pit, START was directed by the TM to collect the soil sample from the staged excavated material in order to be able obtain the required volume for laboratory analysis. Also, only one sample was collected from Test Pit Location No. 4 instead of the proposed two samples; the cause for the sample number reduction was the presence of a large amount of non-soil test pit material.

The Sampling QA/QC Plan indicated that a maximum of seven test pits would be excavated and sampled. At the request of the TM, START collected one standard surface soil sample (Sample No. CDE-S29) in place of one of the canceled test pit samples; the sample location was selected based on the presence of materials similar to those encountered at Test Pit No. 5. Also at the request of the TM, a surface soil sample location initially proposed to be collected from the gravel driveway (Sample No. CDE-S25) was relocated within the fenced truck driving school area. These samples will be analyzed for the same parameters as the originally proposed samples (i.e., TCL PCBs and Ag, Cr, Cd, Hg, and Pb). No subsurface soil sample was collected at these locations.

The soil samples collected on 16 July 1996 were monitored by START for storage cooler temperature until delivery to the laboratory on 17 July 1996. The rinsate blanks were prepared using demonstrated analyte-free deionized water.

9.	Report Prepared by: Jan Bould Date:	07/29/96
10.	Report Reviewed by: Out / P Date:	
11.	Report Approved by: Model attack Date:	7/29/94



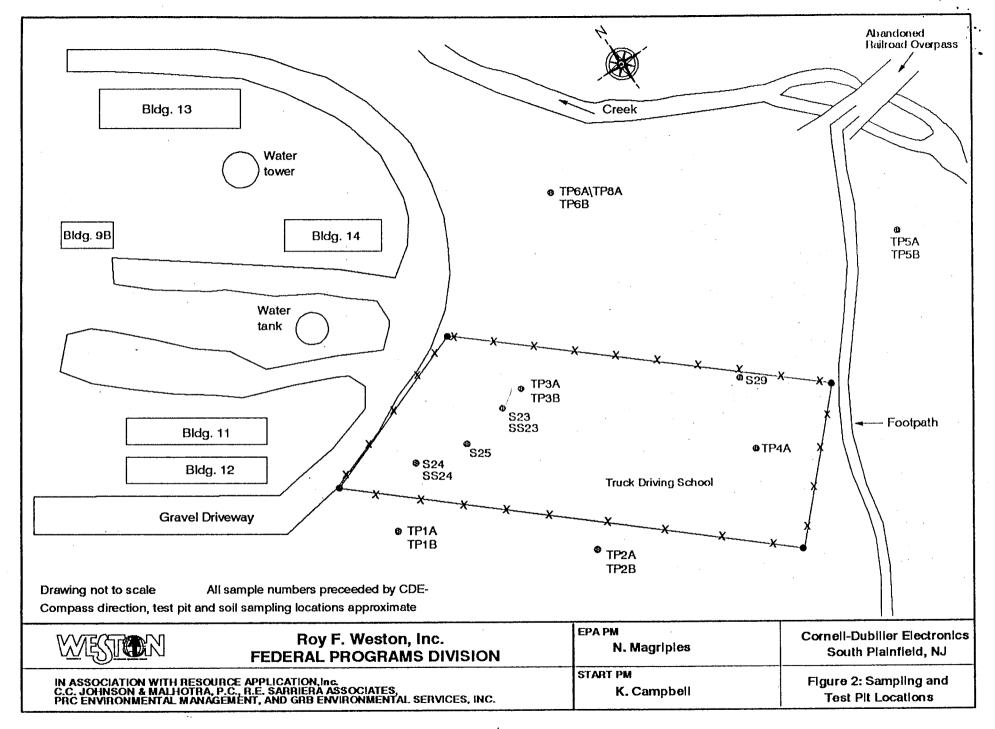


Table 1: Sample Descriptions Cornell-Dubilier Electronics South Plainfield, NJ Sampling Date: 16 July 1996

Sample Number	Time	Matrix	Sample Type	Analysis	Sample Depth [feet]	Location
CDE-TP1Aª	0950	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	2	Test Pit No. 1 (same location as Sample Nos. CDE-S1 and CDE-SS1); 125 ft. southeast of west corner post of driving school fence, then 40 ft. southwest.
CDE-TP1B	1005	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	4.5	Same location as Sample No. CDE-TP1A.
CDE-TP2A	1055	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	2	Test Pit No. 2 (same location as Sample Nos. CDE-S2 and CDE-SS2); 280 ft. southeast of west corner post of driving school fence, then 25 ft. southwest.
CDE-TP2B	1105	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	4	Same location as Sample No. CDE-TP2B.
CDE-TP6A	1215	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3.5	Test Pit No. 6 (20 ft. northeast of location of Sample Nos. CDE-S11 and CDE SS11); 234.6 ft. northwest, along fence line, from east corner post of driving school fence, then 111.4 ft. northeast.
CDE-TP8Ab	1215	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3.5	Same location as Sample No. CDE-TP6A.
CDE-TP6B	1230	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	8.5	Same location as Sample No. CDE-TP6A.

 $^{^{\}rm a}$ MS/MSD sample - indicates additional sample volume was submitted to the laboratory for matrix spike/matrix spike duplicate (MS/MSD) analysis.

^b Duplicate sample - indicates that the sample was collected as an environmental field duplicate.

Table 1: Sample Descriptions Cornell-Dubilier Electronics South Plainfield, NJ Sampling Date: 16 July 1996

Sample Number	Time	Matrix	Sample Type	Analysis	Sample Depth [feet]	Location
CDE-S25	1338	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0 - 0.25	Under truck driving school tent; 114 ft. southeast of the west corner fence post, then 61 ft. northeast.
CDE-S24	1400	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0 - 0.5	Within driving school fenced area; 60 ft. southeast of the west corner fence post, then 27 ft. northeast.
CDE-SS24	1415	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0.8	Same location as Sample No. CDE-S24.
CDE-S23	1410	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0 - 0.5	Within driving school fenced area; 60 ft. southeast from north corner fence post, then 75 ft. southwest.
CDE-SS23	1420	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0.5 - 1	Same location as Sample No. CDE-SS23.
CDE-TP5A	1450	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	4	Test Pit No. 5; (same location as Sample Nos. CDE-S6 and CDE-SS6); 87 ft. northeast of east corner post of driving school fence, the 28 ft. southeast.
CDE-TP5B	1500	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	9	Same location as Sample No. CDE-TP5A.
CDE-TP3A	1545	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	4	Test Pit No. 3; within the driving school fence; 70 ft. southeast of north corner fence post, then 45 ft. southwest.
CDE-TP3B	1600	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	9	Same location as Sample No. CDE-TP3A.
CDE-TP4A	1650	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	6	Test Pit No. 4; sample collected from pile of excavated material; 280 ft. southeast of north corner fence post, then 92 ft. southwest.

Table 1: Sample Descriptions Cornell-Dubilier Electronics South Plainfield, NJ Sampling Date: 16 July 1996

Sample Number	Time	Matrix	Sample Type	Analysis	Sample Depth [feet]	Location
CDE-S29	1715	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-0.5	Inside the driving school fence; 270 ft. southeast of north corner fence post, then 2 ft. southwest.
CDE-RIN3	1310	Aqueous	Composite	TCL PCBs, TAL analytes	N/A	Composite trowel, bowl, and auger rinsate collected in the field.